

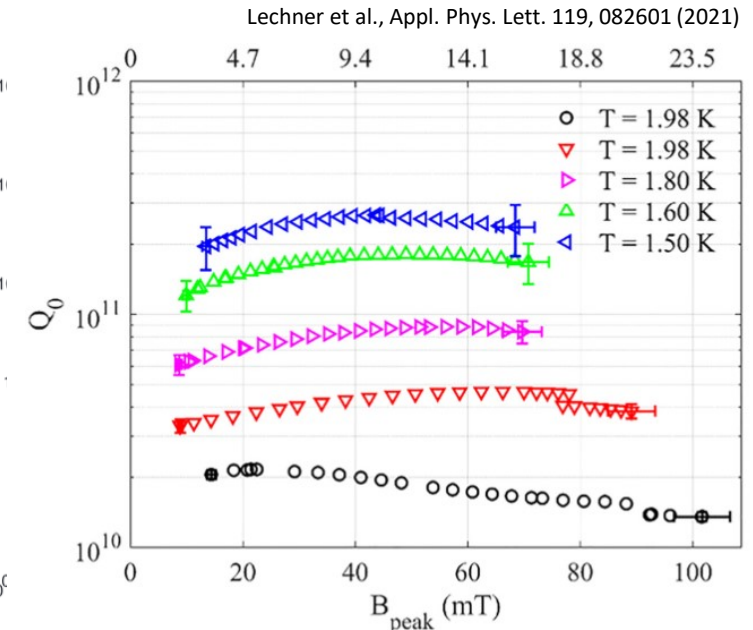
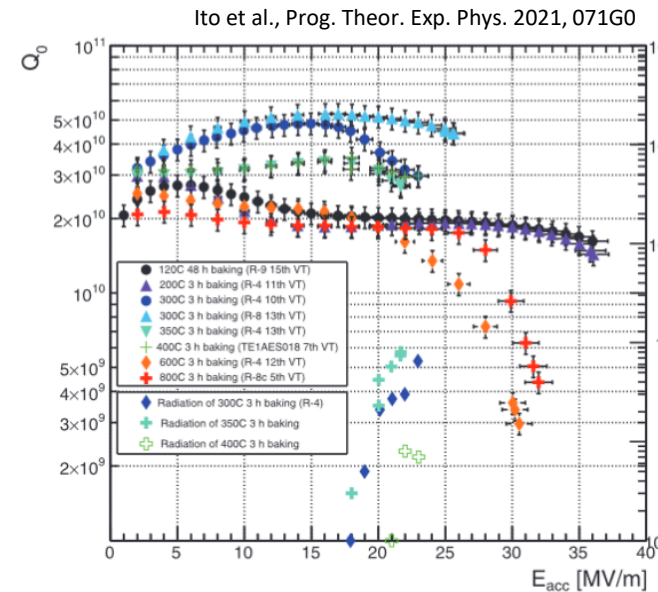
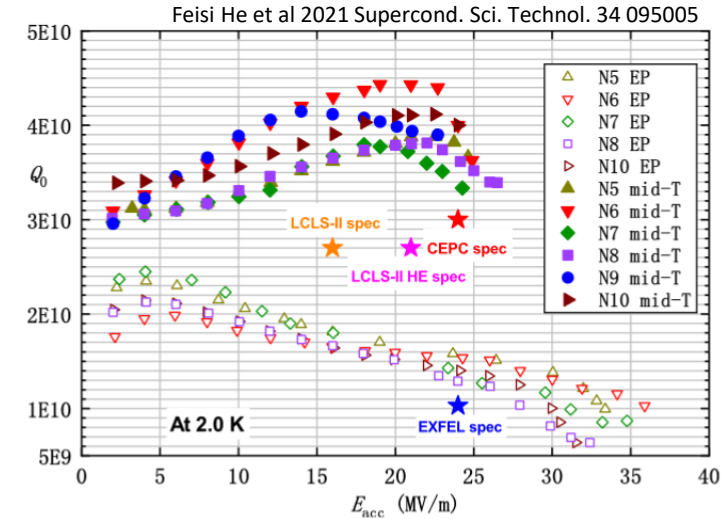
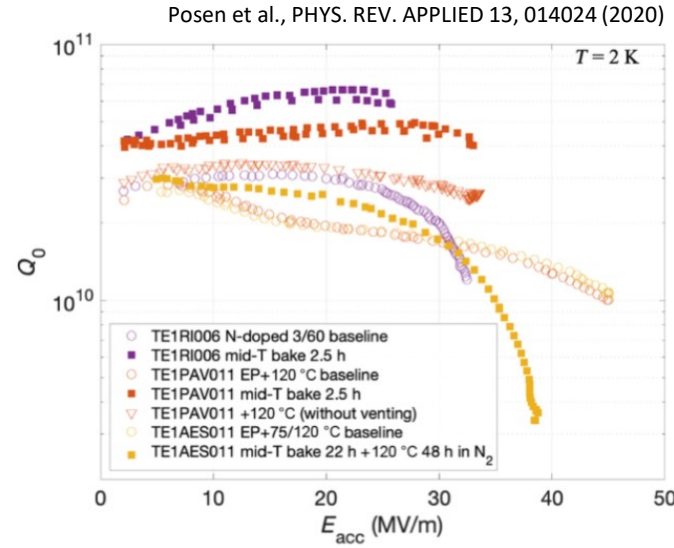
Impact of medium temperature heat treatment on flux trapping sensitivity in SRF cavities

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Background

- Over the last decade, SRF technology progressed towards achieving high Q_0 , with material “doping”, “Infusion”, “alloying”
- Although active area of research, high Q_0 is understood due to the reduction in BCS surface resistance due to the presence of impurities and Q-rise arise from the change in quasi-particle density of states.
- Recent processing technique was focused on medium temperature baking (200- 400 °C) due to its simple process.
- Due to the presence of impurities, the additional rf loss is introduced due to residual flux trapping.



Current Study

- Two 1.3 GHz TESLA shaped single cell cavities, namely TE1-05 and TE1-06 were used for this current study. The cavities were previously heat treated at higher temperature (1000 °C) followed by 25 μm electropolishing to ensure that the cavity provides good flux expulsion.
- Before mid-T heat treatment, the cavities were high pressure rinsed with de-ionized water, dried in a class 10 clean room, installed clean Nb foils in the beam-tube opening, and transported to the furnace.
- The furnace temperature was increased at a rate of $\sim 2 - 5$ °C / min until it reached the target temperature. The furnace was held at the desired temperature for 3 hours and cooled to room temperature.
- The RF measurements consist of $Q_0(T)$ at low peak rf field $B_p \sim 15$ mT at $Q_0(B_p)$ at 2.0 K was measured with two different condition of flux trapping (< 1 mG and ~ 20 mG)
- Flux trapping sensitivity was calculated using:

$$S = \frac{R_{i,B_2} - R_{i,B_1}}{B_2 - B_1}$$

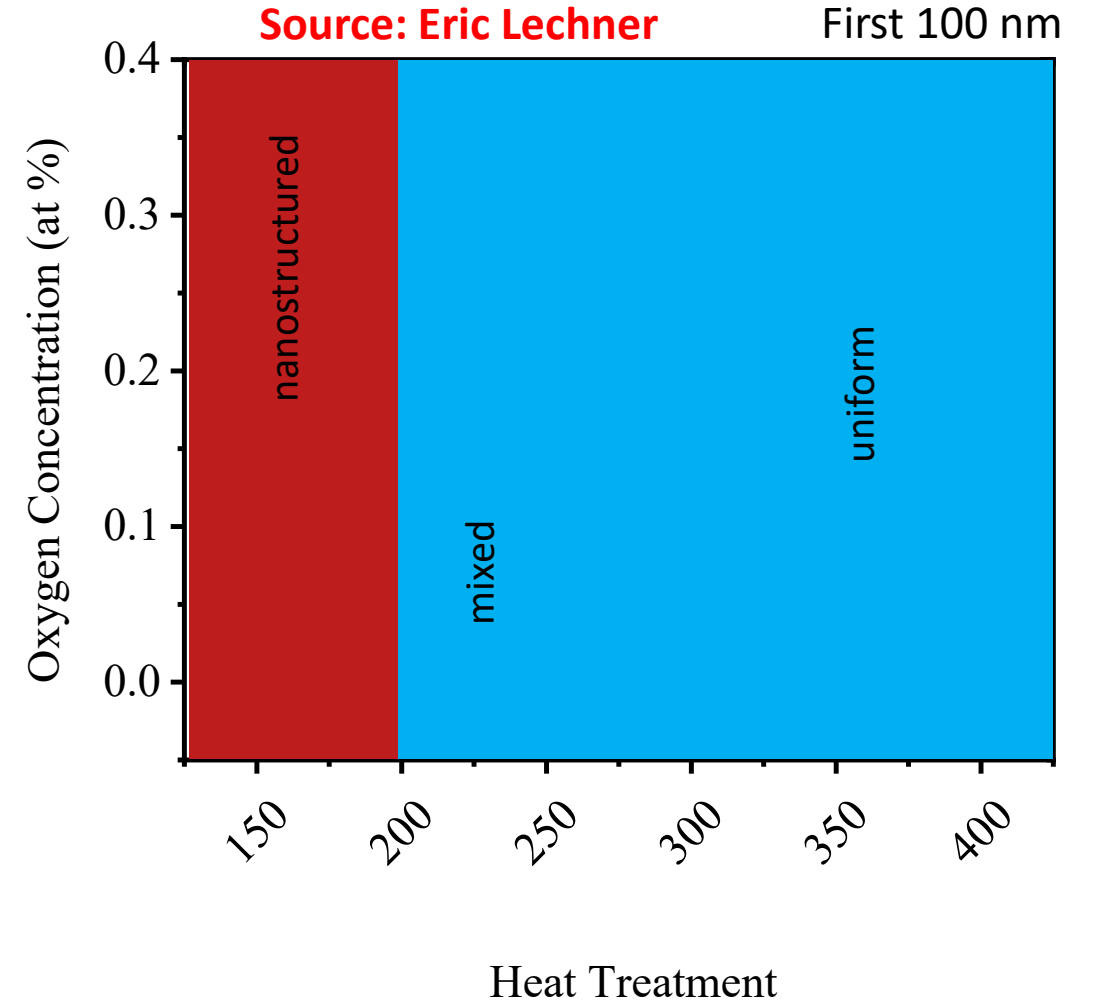
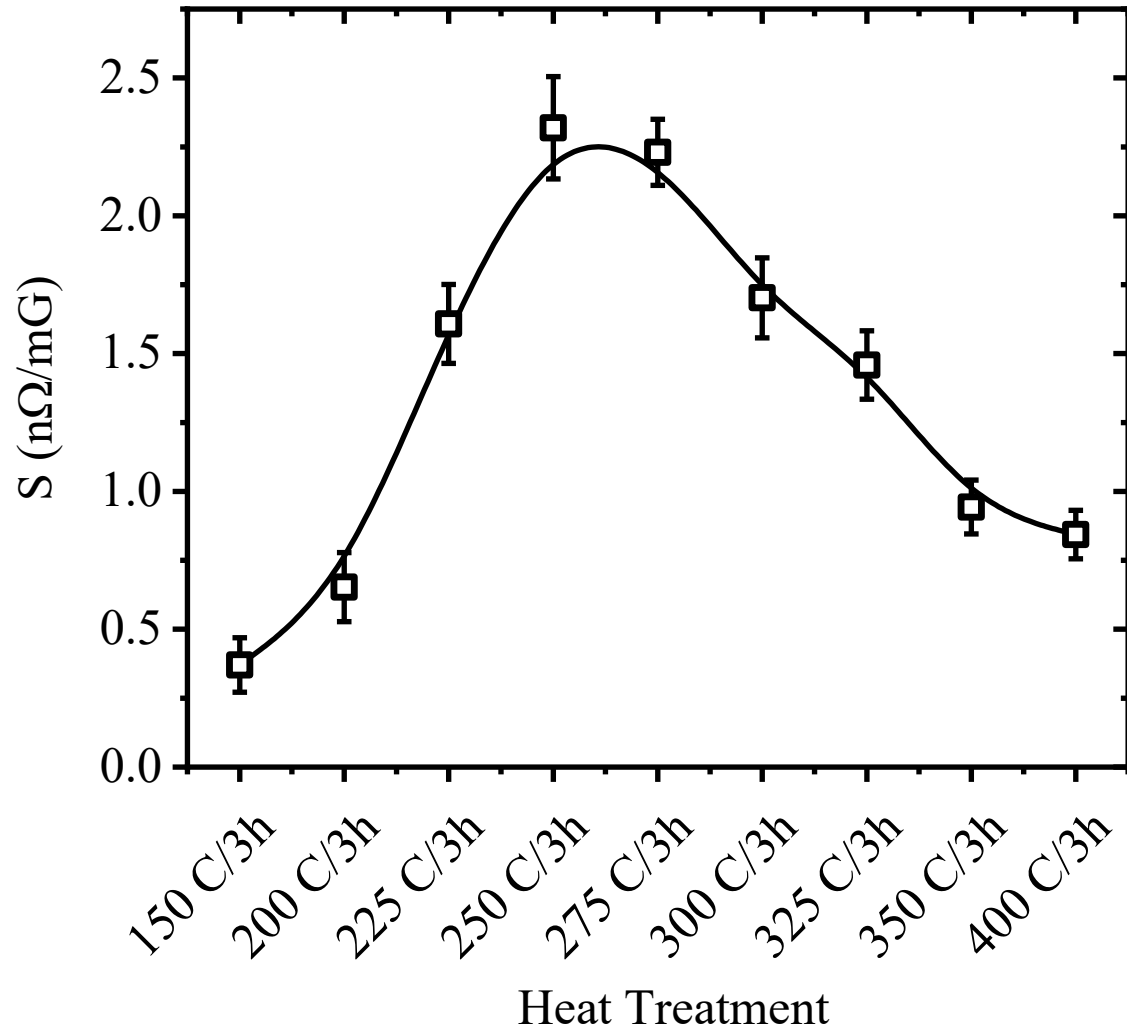
R_i = Residual resistance

$$S = \frac{R_{s,B_2} - R_{s,B_1}}{B_2 - B_1}$$

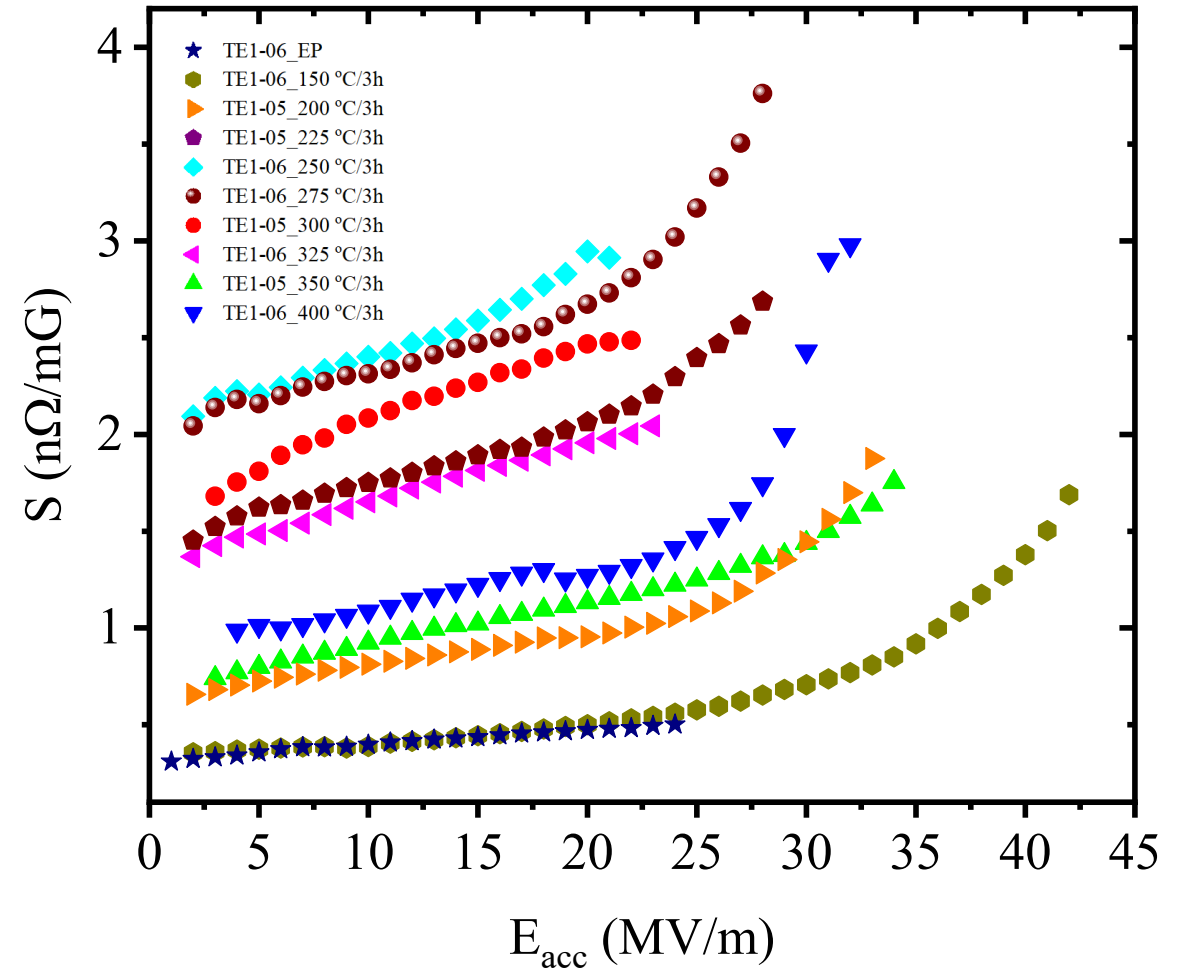
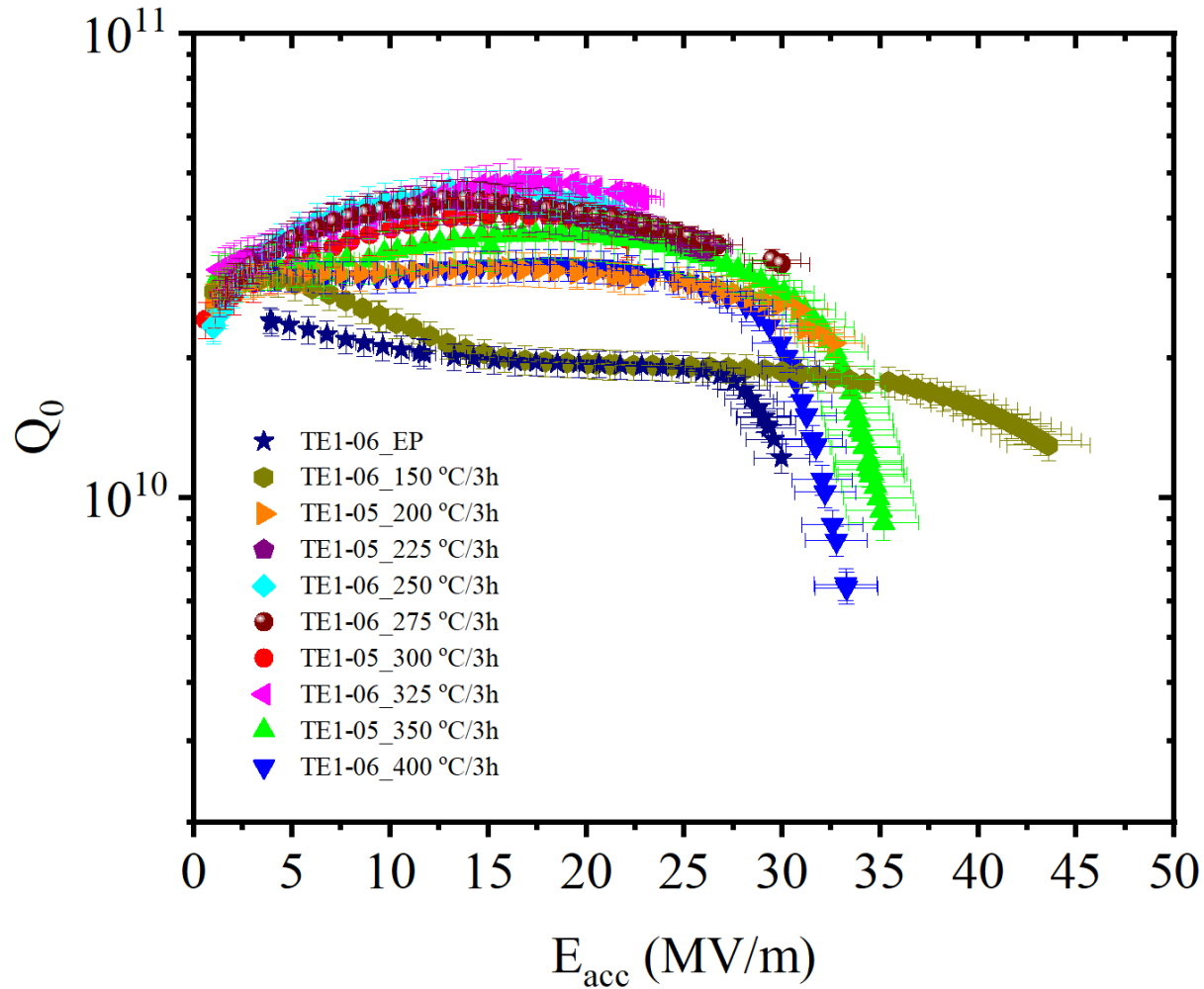
R_s = Surface resistance at 2 K



Flux trapping sensitivity from residual resistance



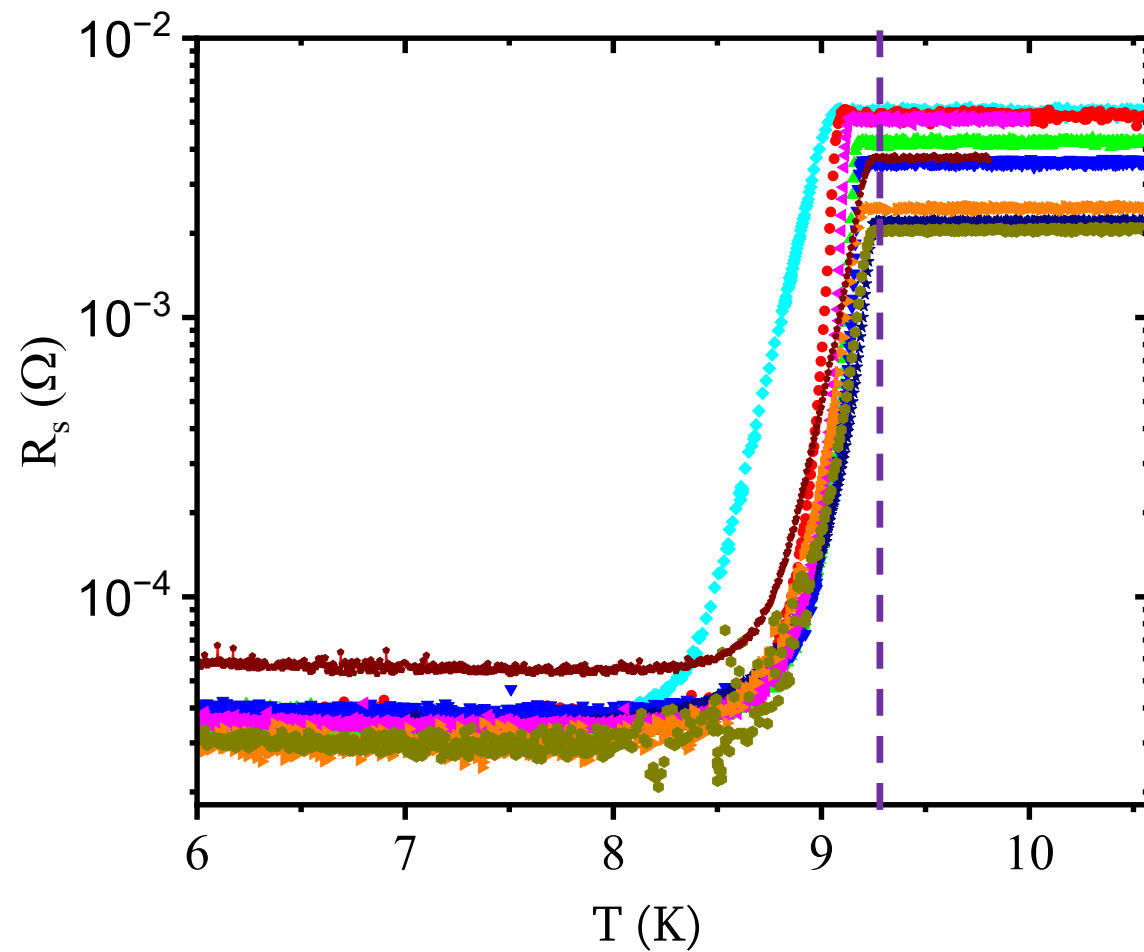
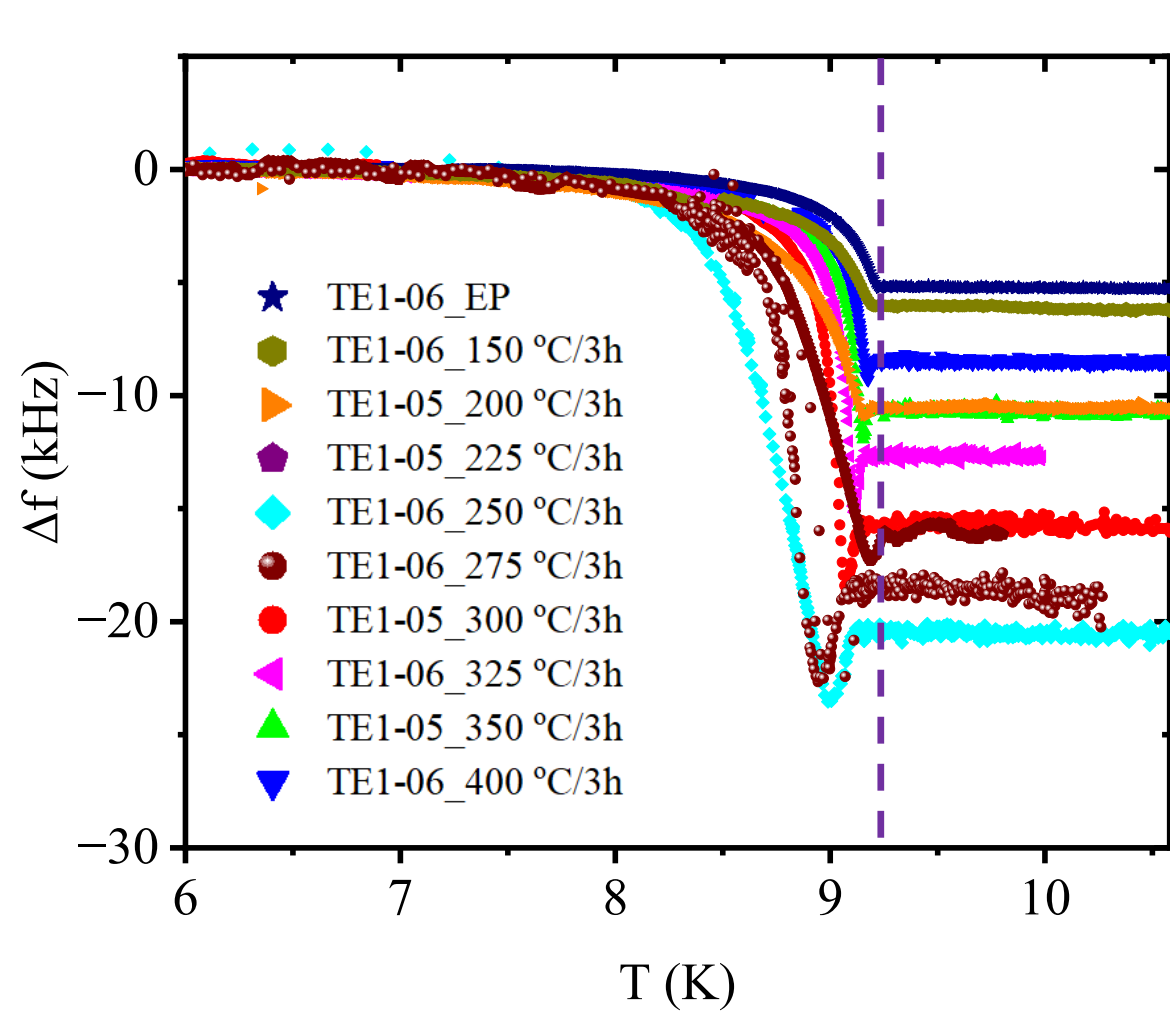
$Q_0(E_{acc})$ and 2.0 K and field dependence of S



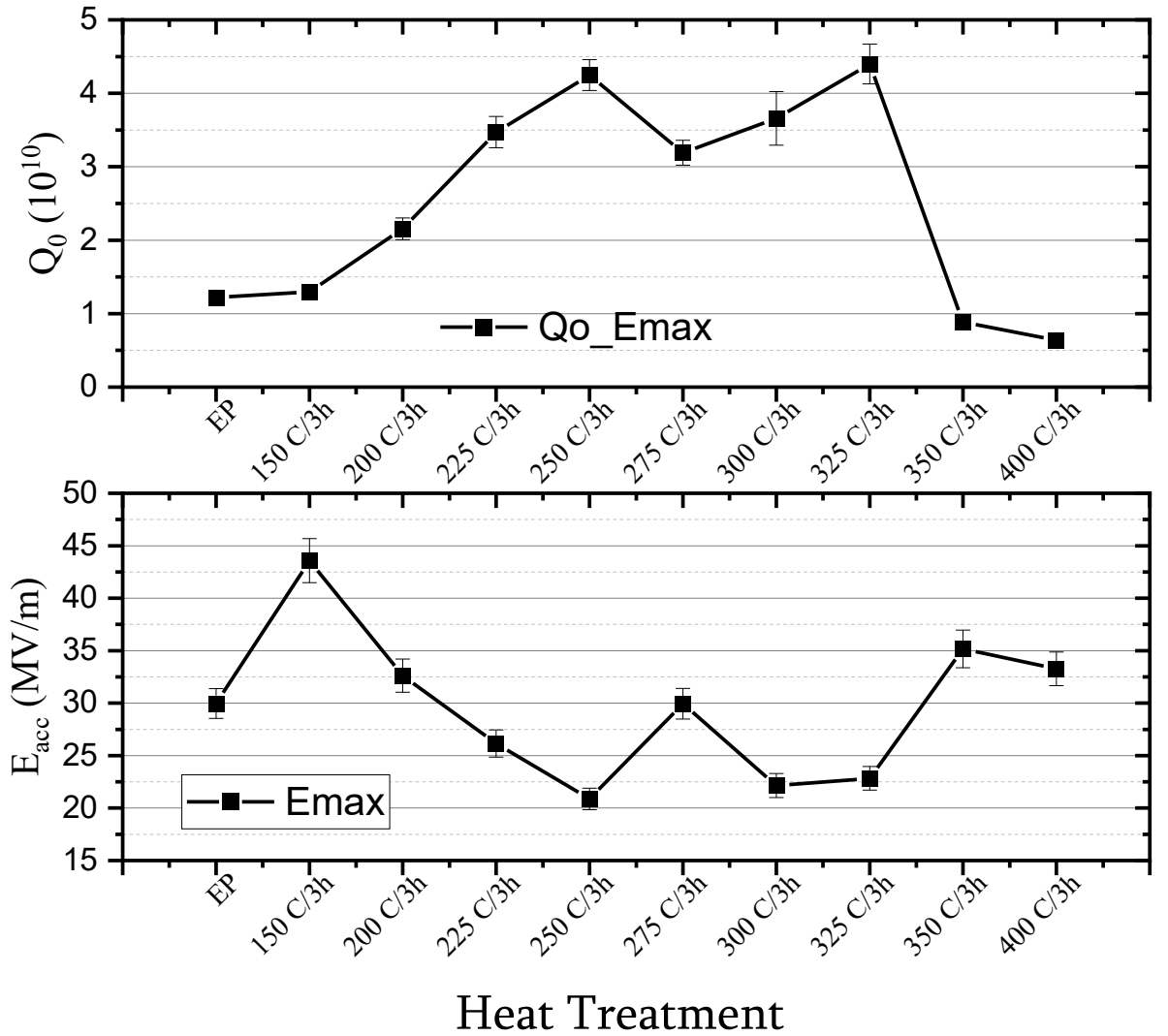
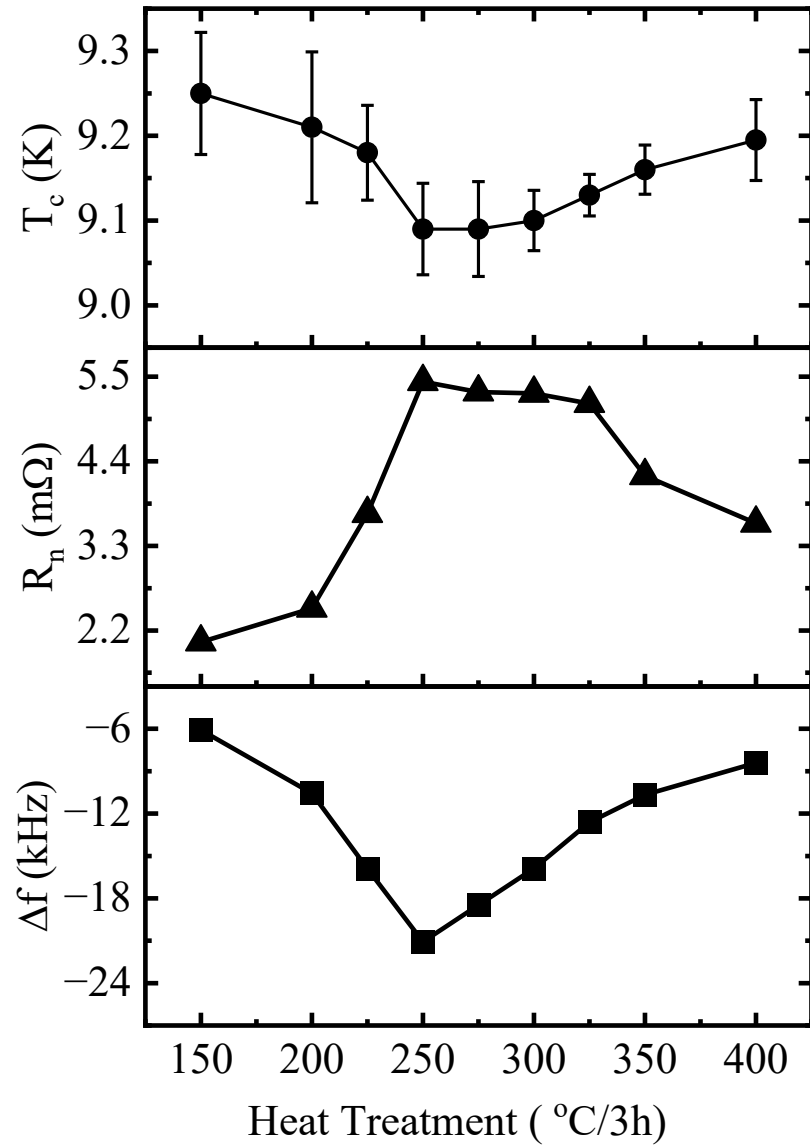
Similar observation by Ito et al



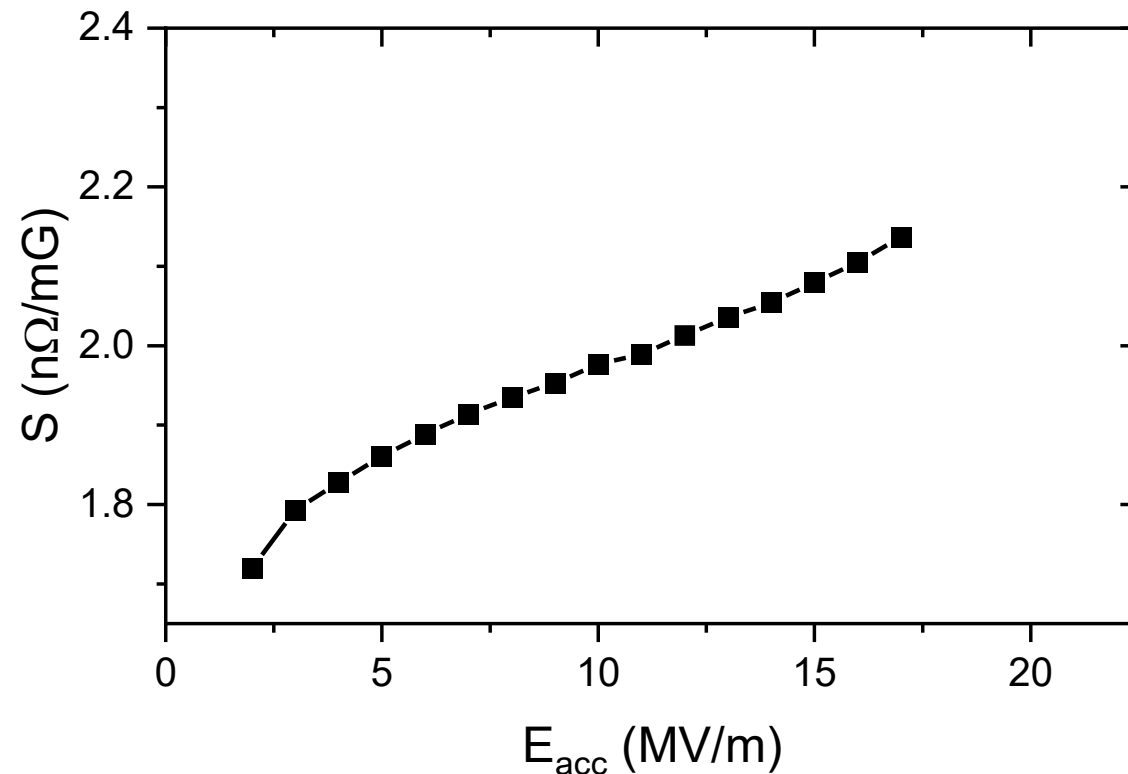
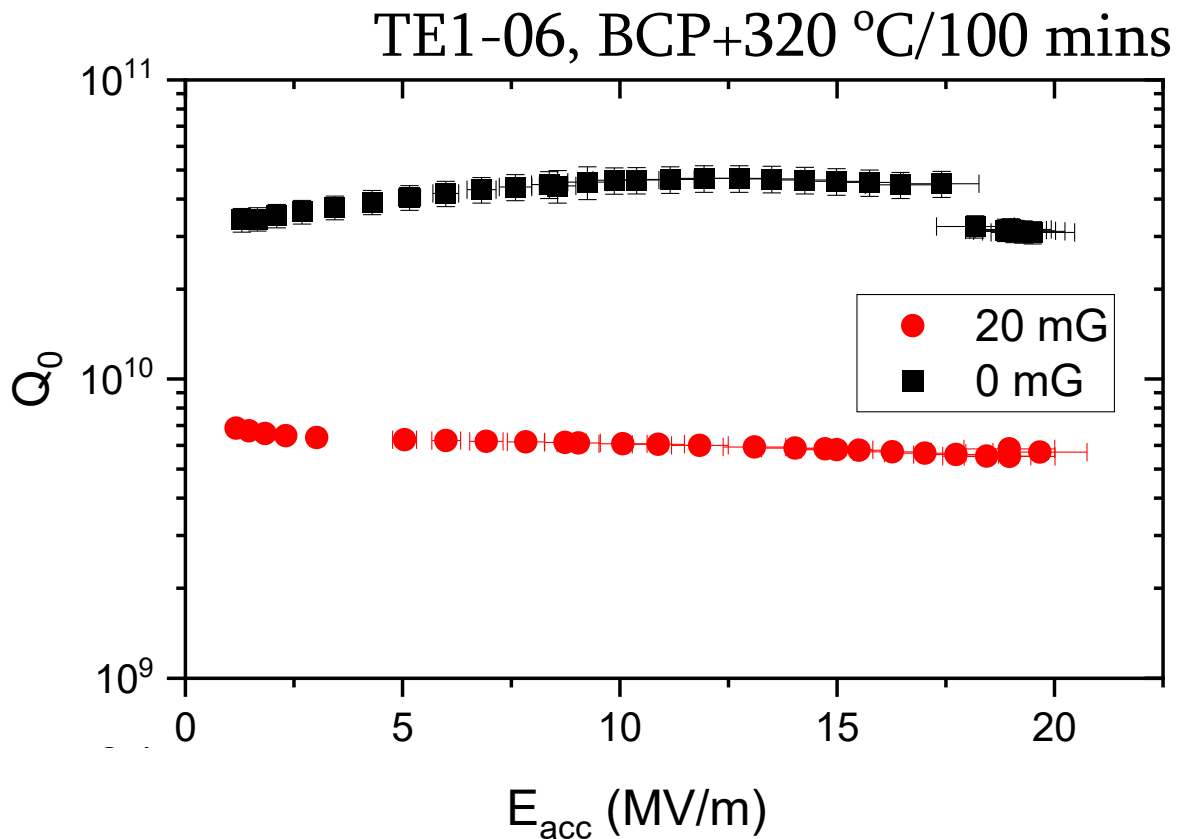
Frequency and Q_0 during warm up



RF Results Summary



Mid T on BCP treated cavity



Mid-T works on BCP treated cavities as well



Summary

- The enhancement of the quality factor through Q-rise is evident following heat treatments within the temperature range of 200 to 400 °C over a duration of 3 hours
- Cavities treated within the temperature range of 250 to 325 °C/3h exhibit a tendency to quench at lower gradients (20 - 25 MV/m) compared to cavities treated outside of this temperature range.
- Several instances of strong multipacting were observed at this gradient range in contrast to the baseline EP'ed cavities, suggesting a possible surface modification due to heat treatment, which causes a change in secondary electron emission yield.
- The sensitivity to flux trapping increases with rising heat treatment temperatures within the range of (200 - 325 °C/3h) and the sensitivity to flux trapping gradually diminishes with increasing heat treatment temperatures.
- The feature on frequency near T_c and change in T_c shows the redistribution of the oxide on the Nb surface due to heat treatment.
- The reappearance of high field Q-slope when heat treatment temperature higher than 350 °C, still need further investigation.

